

TSC321/322/323/324 NAND Gates

- Quad 2-Input (Active Pullup)
- Dual 5-Input (Active Pullup)
- Quad 2-Input (Open Collector)
 - Quad 2-Input (Passive Pullup)

Features

321/322

- IDEAL FOR DRIVING LINES UP TO 10 FEET
- 5mA DRIVE CURRENT IN "1" STATE
- EXPANDER INPUTS
- ACTIVE PULLUP

323/324

- COLLECTOR OR'ABLE
- EXPANDER INPUTS
- 323 SINKS UP TO 11.5 mA (C TYPE) OR 14.0 mA (A TYPE)
- 323 OUTPUT LEVELS ADJUSTABLE TO DTL, TTL OR MOS LEVELS
- 324 HAS PULLUP RESISTORS ON CHIP
- 324 SINKS UP TO 16.8 mA (C TYPE) OR 20.8 mA (A TYPE)

Logic Diagrams

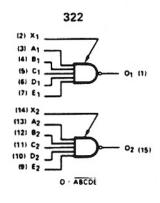
General Descriptions

321/322

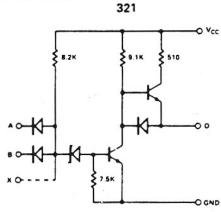
The 321 and 322 are expandable gates with active pullup outputs. Their 5 mA drive currents allow them to drive moderately long lines with no loss of noise immunity.

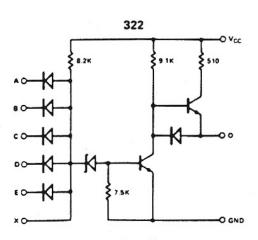
323/324

The 323 and 324 are expandable NAND gates for applications such as "wire-OR" logic systems and interfaces with other logic families. Two gates in each package have expander inputs. The 323 is used with an external pullup resistor while the 324 has pullup resistors on the chip.

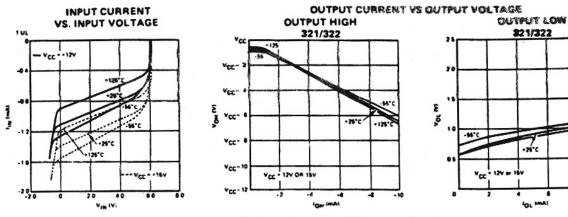


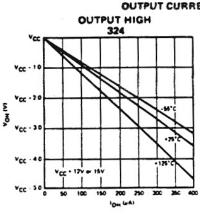
Equivalent Circuits

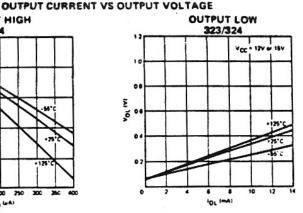




Typical Performance Characteristics

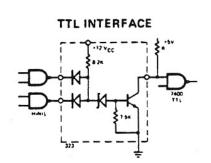






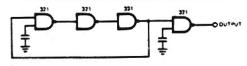
Typical Applications

Rules for selecting external resistors and calculating fanout with collectors OR'd are given in the applications notes. The external resistor of the 323 may be connected to a voltage other than VCC to adjust the output voltage level. The expandable gates may be provided any number of inputs by adding 331 gate expanders or 1N914 diodes (or any 20-volt silicon diodes) to the expander inputs.



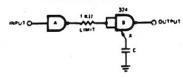
Choose the value of pullup resistor R by the rules given in the applications notes, with $V_{CC} = 5V$.

FREE-RUNNING MULTIVIBRATOR



This self-starting circuit even works without capacitors. PW \cong 1.5 usec. $f\cong$ 3MHz.

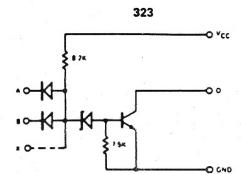
SYSTEM MONITOR

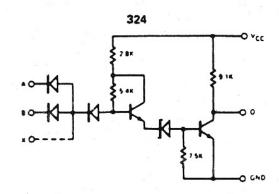


This circuit is used in applications such as detecting presence of data on a normally quiet line, or detecting malfunctions represented by an absence of pulses on a normally active line. A steady succession of pulses at the input holds the output high, but the output goes low if the input remains low for longer than a minimum time established by the value of C. A high input allows C to discharge, switching gate B to a high output. However, a low input causes C to charge at a rate t = C (8.2K) where 8.2K is B's input resistor (internal). For B's output to switch to low, the input to gate A must go low long enough for C to charge above the threshold of gate B. Any new input pulse retriggers the circuit and switches the output to high.

NAND Gates 321, 322, 323, 324

Equivalent Circuits (contd.)





Specifications

321

ICC (WORST-CASE)	15 mA 6	9 13V, 20 mA @ 16V
tPD I/O FUNCTION FOR tPD		300 ns A-O+

322

ICC (WORST-CASE)	8 mA @ 13V, 11 mA @ 16V	
tpD	190 ns	550 ns
I/O FUNCTION FOR tpD	A+O-	A-O+

323

ICC (WORST-CASE)	5.5 mA	@ 13V,8 mA @ 16∨
tPD	160 ns	400 ns
I/O FUNCTION FOR tPD	A+O-	A-O+

324

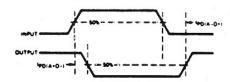
ICC (WORST-CASE)	28 mA @	13V, 40 mA @ 16V
tPD WO FUNCTION FOR tPD		600 ns A-O+

NOTE:

I_{CC} is tested at V_{CC} +1 Volt (+13V for C type and +16V for A type) and is guaranteed across the applicable temp range. t_{PD} is guaranteed at V_{CC} ±1V and across the applicable temp range with the output loaded with 5 unit loads.

See page 12 for electrical summary data.

Switching Time Waveform



Loading Table

PINS	FUNCTION	LOADING
A, B, A-E	Input	1 UL
X	Expanders	Each diode tied to X1 or
		X2 is 1 unit load
0	Outputs	5 UL (321, 322, 324)
		7 UL (324 with
		supplemental 10 kΩ
		pullup resistor)

323 also handles 4 TTL loads at 400 mV.